



NOTES

1. OPERATION WAVELENGTH: 1.2 μm –8.0 μm
2. CLEAR APERTURE: >90%CA
3. DIAMETER TOLERANCE: +0.00/–0.20 mm
4. THICKNESS TOLERANCE: ± 0.1 mm
5. SURFACE QUALITY(S1,S2): 40/20(S/D)
6. SURFACE FLATNESS(S1,S2): $\lambda/2@632.8$ nm
7. PARALLELISM(S1,S2): <2 arcmin
8. CHAMFER: <0.2 mm, 45°
9. COATING(S1,S2): UNCOATED

DRAWING PROJECTION			LBTEK			
	NAME	DATE	OW1–Si			
DRAWN	LZHOU	Aug./12th/24	FLAT WINDOW UNCOATED $\phi 12.7$ mm \times 3 mm			
APPROVAL	WCHENG	Aug./12th/24	MATERIAL	WEIGHT	SCALE	REV
FOR INFORMATION ONLY NOT FOR MANUFACTURING PURPOSES			Si	0.9 g	5:1	A